

Main Product Characteristics

V _{DSS}	500V		
R _{DS} (on)	0.2Ω (typ.)		
I _D	20A ①		



TO-247

G D S Marking and Pin

Assignment

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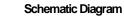
SSF20N50UH



Features and Benefits

- Advanced Process Technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery







Description

These N-Channel enhancement mode power field effect transistors are produced using silikron proprietary MOSFET technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switch mode power supplies.

Absolute Max Rating

Symbol	Parameter	Max.	Units		
I _D @ TC = 25°C	Continuous Drain Current, V _{GS} @ 10V	20 ①			
I _D @ TC = 100°C	Continuous Drain Current, V _{GS} @ 10V	12.6 ①	А		
I _{DM}	Pulsed Drain Current 2	80	1		
	Power Dissipation 3	250	W		
P _D @TC = 25°C	Linear Derating Factor	2.0	W/°C		
V _{DS}	Drain-Source Voltage		V		
V _{GS} Gate-to-Source Voltage		± 30	V		
E _{AS} Single Pulse Avalanche Energy @ L=6.5mH		1433	mJ		
I _{AS}	Avalanche Current @ L=6.5mH	21	А		
T _J T _{STG}	Operating Junction and Storage Temperature Range	-55 to +150	°C		



Thermal Resistance

Symbol	Characteristics	Тур.	Max.	Units
R _{θJC}	Junction-to-case 3	—	0.5	°CW
R _{0JA}	Junction-to-ambient (t \leq 10s) (4)	—	50	°C /W

Electrical Characteristics $@T_A=25^{\circ}C$ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions	
V _{(BR)DSS}	Drain-to-Source breakdown voltage	500	_	_	V	$V_{GS} = 0V, I_D = 250 \mu A$	
Р	Static Drain-to-Source on-resistance		0.2	0.27	Ω	V_{GS} =10V,I _D = 10A	
R _{DS(on)}	Static Drain-to-Source on-resistance		0.47	—		T _J = 125°C	
V	Gate threshold voltage	2	—	4	V	$V_{DS} = V_{GS}, I_D = 250 \mu A$	
V _{GS(th)}	Gale meshold voltage	_	1.4	—	v	$T_J = 125^{\circ}C$	
1	Drain to Source lookage ourrent	_	—	1		$V_{DS} = 500 V, V_{GS} = 0 V$	
I _{DSS}	Drain-to-Source leakage current	_	—	50	μA	$T_J = 125^{\circ}C$	
I _{GSS} Gate-to-Sour	Cata to Source forward lookage	—	—	100	nA	$V_{GS} = 30V$	
	Gate-to-Source forward leakage		—	-100		V _{GS} = -30V	
Qg	Total gate charge		48	_		I _D = 20A,	
Q_{gs}	Gate-to-Source charge	_	16	—	nC	V _{DS} =400V,	
Q_{gd}	Gate-to-Drain("Miller") charge	—	13	—		$V_{GS} = 10V$	
t _{d(on)}	Turn-on delay time	_	18	—			
tr	Rise time		64	—	ns	V_{GS} =10V, V_{DS} =250V,	
t _{d(off)}	Turn-Off delay time	_	51	—	115	R_{GEN} =3.9 Ω , R_{L} =12 Ω	
t _f	Fall time	_	49	_			
Ciss	Input capacitance	_	2778	_		$V_{GS} = 0V$	
Coss	Output capacitance	_	350	_	pF	V _{DS} = 25V	
C _{rss}	Reverse transfer capacitance		3.1	_		f = 1MHz	

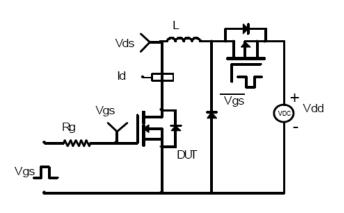
Source-Drain Ratings and Characteristics

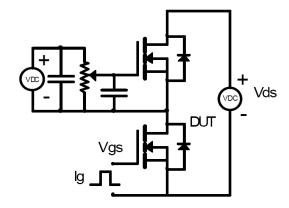
Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
I _S	Continuous Source Current		Ι	20 ①	А	MOSFET symbol
	(Body Diode)					showing the
I _{SM}	Pulsed Source Current		_	80	А	integral reverse
	(Body Diode)	_				p-n junction diode.
V _{SD}	Diode Forward Voltage		1.0	1.4	V	I _S =20A, V _{GS} =0V
t _{rr}	Reverse Recovery Time	_	570	—	nS	$T_J = 25^{\circ}C, I_F = 20A,$
Qrr	Reverse Recovery Charge		7.35	_	μC	di/dt = 100A/µs



Test circuits and Waveforms

EAS Test Circuit

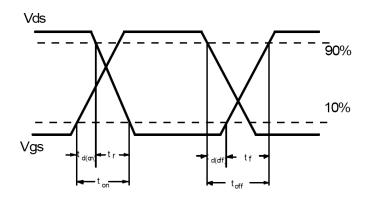




Switching Time Test Circuit

Switching Waveforms

Gate charge test circuit



Notes:

- ①Calculated continuous current based on maximum allowable junction temperature.
- 2 Repetitive rating; pulse width limited by max. junction temperature.
- ③The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- (4) The value of $R_{\theta JA}$ is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with TA =25°C



Typical electrical and thermal characteristics

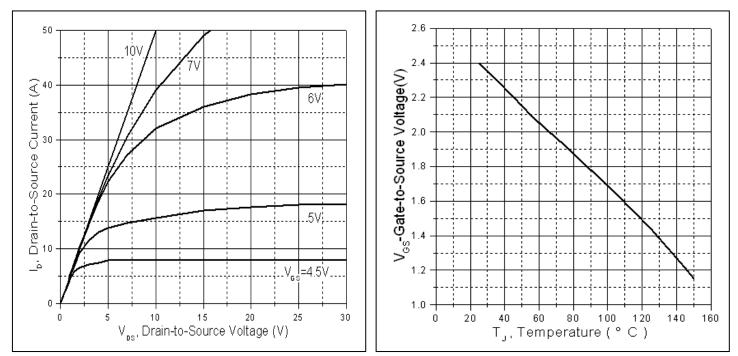
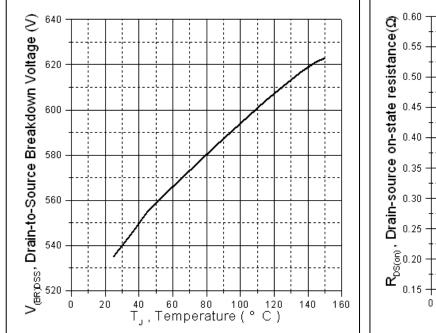
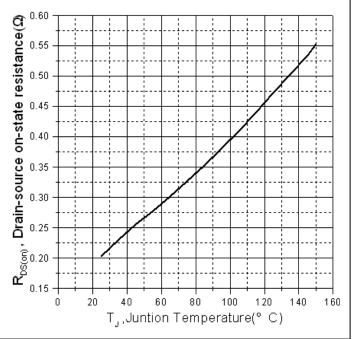


Figure 1.Typical Output Characteristics





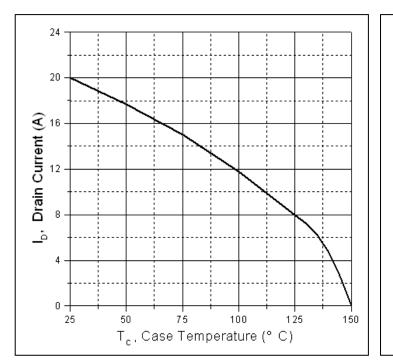












Typical electrical and thermal characteristics



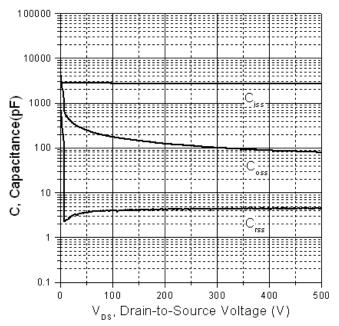
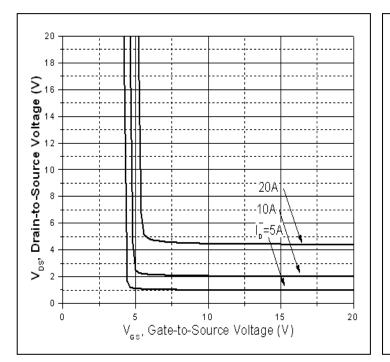


Figure 6. Typical Capacitance Vs. Drain-to-Source Voltage



1 D = 0.5 0.2 0.1 ‡0.1 0.05 ₿▲ 0.02 0.01 single pulse Т 4 . F. D. OTQ 0.001 1E-06 1E-05 1E-04 1E-03 1E-02 1E-01 1E+00 1E+01 Pulse width, tp (s)

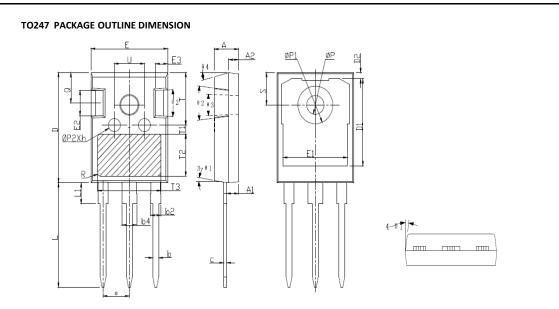
Zth j-mb (K/W)

Figure7. Drain-to-Source Voltage Vs. Gate-to-Source Voltage





Mechanical Data:



Symbol	Dimension In Millimeters			Dimension In Inches			
Symbol	Min	Nom	Max	Min	Nom	Max	
А	4.900	5.000	5.100	0.193	0.197	0.201	
A1	2.310	2.410	2.510	0.091	0.095	0.099	
A2	1.900	2.000	2.100	0.075	0.079	0.083	
b	1.160	1.210	1.260	0.046	0.048	0.050	
b2	1.960	2.010	2.060	0.077	0.079	0.081	
b4	2.960	3.010	3.060	0.117	0.119	0.120	
С	0.590	0.610	0.660	0.023	0.024	0.026	
D	20.900	21.000	21.100	0.823	0.827	0.831	
D1	16.250	16.550	16.850	0.640	0.652	0.663	
D2	1.050	1.200	1.350	0.041	0.047	0.053	
E	15.700	15.800	15.900	0.618	0.622	0.626	
E1	13.100	13.300	13.500	0.516	0.524	0.531	
E2	4.900	5.000	5.100	0.193	0.197	0.201	
E3	2.400	2.500	2.600	0.094	0.098	0.102	
e		5.44BSC			0.214BSC		
h	0.050	0.100	0.150	0.002	0.004	0.006	
L	19.800	19.920	20.100	0.780	0.784	0.791	
L1	-	-	4.300	-	-	0.169	
ΦP	3.500	3.600	3.700	0.138	0.142	0.146	
ΦΡ1	-	-	7.300	-	-	0.287	
ΦP2	2.400	2.500	2.600	0.094	0.098	0.102	
Q	5.600	5.800	6.000	0.220	0.228	0.236	
S		6.15BSC			0.242BSC		
R		0.50BSC			0.020BSC		
Т	9.800	-	10.200	0.386	-	0.402	
T1		1.65REF			0.065REF		
T2		8.00REF			0.315REF		
T3	12.80REF				0.504REF		
U	6.000	-	6.400	0.236	-	0.252	
θ1	6°	7°	8°	6°	7°	8°	
θ2	4°	5°	6°	4°	5°	6°	
θ3	1°	-	1.5°	1°	-	1.5°	
θ4	14°	15°	16°	14°	15°	16°	



Ordering and Marking Information

Device Marking: SSF20N50UH
Package (Available)
TO-247
Operating Temperature Range
C : -55 to 150 ⁰C

Devices per Unit

Package Type	Units/ Tube	Tubes/Inner Box	Units/Inner Box	Inner Boxes/Carton Box	Units/Carton Box
TO-247	30	11	330	6	1980

Reliability Test Program

Test Item	Conditions	Duration	Sample Size
High	T _j =125℃ to 150℃ @	168 hours	3 lots x 77 devices
Temperature	80% of Max	500 hours	
Reverse	V _{DSS} /V _{CES} /VR	1000 hours	
Bias(HTRB)			
High	T _j =150℃ @ 100% of	168 hours	3 lots x 77 devices
Temperature	Max V _{GSS}	500 hours	
Gate		1000 hours	
Bias(HTGB)			



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